

CM-460 SERIES



150mm Semi-Automatic Probe Station

The perennial workhorse in the SIGNATONE product offering, the CM-460 Series of 6" semi-automatic analytical probe stations represents mature technology at its best. Based on our proven linear motor technology, which virtually eliminates accuracy and repeatability issues, the CM-460 will deliver years of worry-free performance where and when you need it.



PERFORMANCE, QUALITY, VALUE

SIGNATONE®

Advanced Microprobing Solutions Since 1968

CM-460 SERIES



Specifications

- ♦ 150mm linear motor drive
- ♦ 2-Point software alignment
- ♦ Software Z control
- ♦ 2" & 6" manual/programmable/hybrid microscope transports available
- ♦ Optional 4" microscope lift
- ♦ Chuck X-Y Resolution: $.1\mu$ (1μ S-465)
- ♦ Chuck X-Y Repeatability: $.5\mu$ (1μ S-465)
- ♦ Chuck X-Y Accuracy: 1μ (3μ S-465)
- ♦ Chuck Z Resolution: $.1\mu$
- ♦ Chuck Z Accuracy: $.25\mu$
- ♦ Chuck Θ : 18 degrees

X-Y Motion Control

- ♦ "Point & Shoot" movements
- ♦ 8 directional arrows with variable speed control
- ♦ Wafer map "Pick & Move"
- ♦ "Go To" commands

Z Motion Control

- ♦ Separate contact/overdrive height
- ♦ Z motion speed control
- ♦ Safety lock
- ♦ Soft Z with edge sense circuit (for use w/probe card edge sense)

User-Friendly Features

- ♦ Stores setup and programs for easy retrieval
- ♦ Icons for most applications
- ♦ Basic Run mode guides the user through basic operations
- ♦ On-Screen video display option
- ♦ Wafer map position indicator

Integrated Probing Solutions For Testing

- ♦ CV
- ♦ Vth
- ♦ Tox
- ♦ IV
- ♦ Sub-Threshold
- ♦ Leakage to 5 fA
- ♦ Resistivity
- ♦ WLR
- ♦ Dark Current
- ♦ Pulse mode 10A/100V Measurements

Programming

- ♦ Wafer Map design editor
- ♦ Selective programming
- ♦ Learn position
- ♦ Subroutine with chuck or Computer aided Probe

Interfacing

- ♦ DDE interface integrated with ICS Metrics for instrument control of most Keithley and Agilent instruments
- ♦ Application SW for Keithley 2400 Series
- ♦ DDE compatible with HP VEE
- ♦ DDE compatible with NI LABView
- ♦ GPIB compatible with NI LABView

Other Features

- ♦ Microscope X-Y-Z and Zoom control
- ♦ Color wafer bin mapping with 16 colors
- ♦ Hot chuck interface and control
- ♦ Accepts probe cards
- ♦ Available vibration isolation tables
- ♦ Optional Controller/Instrumentation rack

ICS-Metrics Software

- ICS-Metrics integrates Agilent and Keithley DC/CV instrumentation for the automated characterization of semiconductor parameters
- ♦ Graphical user interface for all instrument functions
- ♦ Simple, pre-configured test formats for semiconductor devices
- ♦ Data collection and storage
- ♦ Sequential test execution
- ♦ Data analysis and reporting

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